HARRIS SEMICONDUCTOR

HARRIS · RCA · GE · INTERSIL

Operational Amplifiers

CA3010A, CA3015A, CA3029A, CA3030A

May 1990

Operational Amplifiers

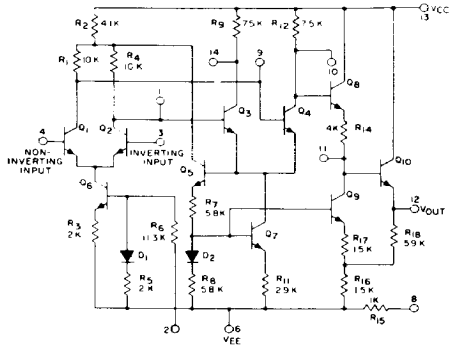
Features:

- *These new types have all the desirable features and characteristics of their prototypes plus lower noise figures and improved input characteristics for offset voltage, offset current, bias current, and impedance*
- *All types are electrically identical within their voltage groups*
- *For use in telemetry, data-processing, instrumentation, and communication equipment*
- *Built-in temperature stability from −55°C to +125°C for TO-5 style, and ceramic dual-in-line packages; 0°C to +70°C for plastic dual-in-line packages*

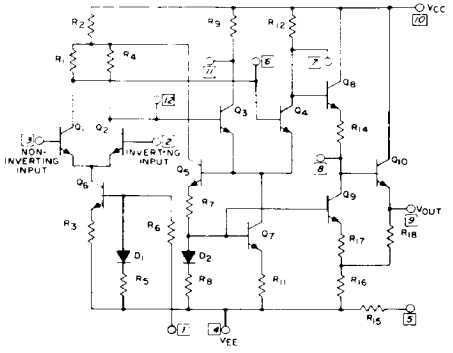
Applications:

- *Narrow-band and band-pass amplifier*
- *Operational functions*
- *Feedback amplifier*
- *DC and video amplifier*
- *Multivibrator*
- *Oscillator*
- *Comparator*
- *Servo driver*
- *Scaling adder*
- *Balanced modulator-driver*

6-VOLT TYPES	12-VOLT TYPES	PACKAGE
CA3010A	CA3015A	12-Lead TO-5 Style
CA3029A	CA3030A	14-Lead Plastic Dual-In-Line (TO-116)



CA3029A, CA3030A



CA3010A, CA3015A

Figure 1 – Schematic diagrams.

File Number **310**

ABSOLUTE-MAXIMUM VOLTAGE AND CURRENT LIMITS, T_A = 25°C

Voltage or current limits shown for each terminal can be applied under the indicated voltage or other circuit conditions for other terminals

All voltages are with respect to ground (common terminal of Positive and Negative DC Supplies)

Terminal		Voltage or Current Limits		Circuit Conditions		
CA3010A	CA3029A	Negative	Positive	Terminal		Voltage
12	1	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
				CA3010A	CA3029A	
1	2	-8 V	0 V	4 10	6 13	-8 +6
2	3	-4 V	+1 V	1 3 4 10	2 4 6 13	0 0 -6 +6
3	4	-4 V	+1 V	1 2 4 10	2 3 6 13	0 0 -6 +6
-	5	NO CONNECTION				
4	6	-10 V	0 V	1 10	2 13	0 +6
-	7	NO CONNECTION				
5	8	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
6	9	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
7	10	0 V	+7 V	1 4 10	2 6 13	0 -6 +6
8	11	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
9	12	30 mA		4 10 200 Ω Between Terminals 6 & 12 CA3029A, 4 & 9 (CA3010A)	6 13	-6 +6
10	13	0 V	+10 V	1 4	2 6	0 -6
11	14	0 V	+7 V	1 4 10	2 6 13	0 -6 +6
CASE		Internally connected to Terminal No.4, CA3010A (Substrate) DO NOT GROUND				

Terminal		Voltage or Current Limits		Circuit Conditions		
CA3015A	CA3030A	Negative	Positive	Terminal		Voltage
12	1	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
				CA3015A	CA3030A	
1	2	-16 V	0 V	4 10	6 13	-16 +12
2	3	-8 V	+1 V	1 3 4 10	2 4 6 13	0 0 -12 +12
3	4	-8 V	+1 V	1 2 4 10	2 3 6 13	0 0 -12 +12
-	5	NO CONNECTION				
4	6	-20 V	0 V	1 10	2 13	0 +12
-	7	NO CONNECTION				
5	8	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
6	9	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
7	10	0 V	+14 V	1 4 10	2 6 13	0 -12 +12
8	11	DO NOT APPLY VOLTAGE FROM AN EXTERNAL SOURCE TO THIS TERMINAL				
9	12	30 mA		4 10 400 Ω Between Terminals 6 & 12 CA3030A, 4 & 9 (CA3015A)	6 13	-12 +12
10	13	0 V	+20 V	1 4	2 6	0 -12
11	14	0 V	+14 V	1 4 10	2 6 13	0 -12 +12
CASE		Internally connected to Terminal No.4, CA3015A (Substrate) DO NOT GROUND				

	CA3010A CA3015A	CA3029A CA3030A
OPERATING TEMPERATURE RANGE	-55°C to +125°C	-40°C to +80°C
STORAGE TEMPERATURE RANGE	-65°C to +200°C	-65°C to +150°C

	CA3030A	CA3015A	CA3029A	CA3010A
MAXIMUM SIGNAL VOLTAGE	-8 V to +1 V		-4 V to +1 V	
MAXIMUM DEVICE DISSIPATION	600 mW		300 mW	

ELECTRICAL CHARACTERISTICS at T_A = 25°C

Characteristics	Symbols	Special Test Conditions Terminal No.8 CA3029A, CA3030A, Terminal No.5 (CA3010A, CA3015A) Not Connected Unless Otherwise Specified	Test Circuit Fig.	CA3010A CA3029A Min.	CA3010A CA3029A Typ.	CA3010A CA3029A Max.	CA3015A CA3030A Min.	CA3015A CA3030A Typ.	CA3015A CA3030A Max.	Units	Typical Characteristic Curves Fig.
STATIC CHARACTERISTICS:											
Input Offset Voltage	V_{IO}	V_{CC} = +6V, V_{EE} = -6V = +12V = -12V	4	- -	0.9 -	2 -	- -	- 1	- 2	mV	2
Input Offset Current	I_{IO}	= +6V = -6V = +12V = -12V	5	- -	0.3 -	1.5 -	- -	- 0.5	- 1.6	μA	2
Input Bias Current	I_{IB}	= +6V = -6V = +12V = -12V	5	- -	2.5 -	4 -	- -	- 4.7	- 6	μA	3
Input Offset Voltage Sensitivity: Positive	$\Delta V_{IO}/\Delta V_{CC}$	= +6V = -6V = +12V = -12V	4	- -	0.10 -	1 -	- -	- 0.096	- 0.5	mV/V	none
Negative	$\Delta V_{IO}/\Delta V_{EE}$	= +6V = -6V = +12V = -12V		- -	0.26 -	1 -	- -	- 0.156	- 0.5		
Device Dissipation	P_D	= +6 V = -6 V = +12V = -12V	4	- -	40 -	- -	- -	- 175	- -	mW	none
		[5] shorted to [9] V_{CC} = +6V, V_{EE} = -6V		-	102	-	-	-	-		
		8 shorted to 12 V_{CC} = +12V, V_{EE} = -12V		-	-	-	-	500	-		
DYNAMIC CHARACTERISTICS: All tests at f = 1 kHz except BW_{OL}											
Open-Loop Differential Voltage Gain	A_{OL}	V_{CC} = +6V, V_{EE} = -6V = +12V = -12V	8	57 -	60 -	- -	- 66	- 70	- -	dB	6 & 7
Open-Loop Bandwidth at -3 dB Point	BW_{OL}	= +6V = -6V = +12V = -12V	8	200 -	300 -	- -	- 200	- 320	- -	kHz	6 & 7
Slew Rate	SR	V_{CC} = +6V V_{EE} = -6V R_S = 1 kΩ = +12V = -12V	none	- -	3 -	- -	- -	- 7	- -	V/μs	none
Common-Mode Rejection Ratio	CMR	V_{CC} = +6V, V_{EE} = -6V = +12V = -12V	11	70 -	94 -	- -	- 80	- 103	- -	dB	12
Maximum Output-Voltage Swing	$V_{O(P-P)}$	= +6V = -6V = +12V = -12V	8	4 -	6.75 -	- -	- 12	- 14	- -	V_{P-P}	9 & 10
Input Impedance	Z_{IN}	= +6V = -6V = +12V = -12V	14	15 -	20 -	- -	- 7.5	- 10	- -	kΩ	13
Output Impedance	Z_{OUT}	= +6V = -6V = +12V = -12V	15	- -	160 -	- -	- -	- 85	- -	Ω	16
Common-Mode Input-Voltage Range	V_{ICR}	= +6V = -6V = +12V = -12V	11	+0.5 to -4 -	- -	- -	- +0.65 to -8	- -	- -	V	none
Noise Figure	NF	V_{CC} = +3V , V_{EE} = -3V = +6V = -6V = +9V = -9V = +12V = -12V R_S = 1 kΩ	18	- - - -	6.3 8.3 - -	9 12 - -	- - - -	6.3 8.3 10 11	9 12 14 16	dB	17

LEAD TEMPERATURE (During Soldering): ALL TYPES

At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10 seconds max. ..... +265°C

TYPICAL DYNAMIC CHARACTERISTICS AND TEST CIRCUITS

Terminal Numbers in Circles are for CA3029A, CA3030A
Italic Numbers in Square Boxes are for CA3010A, CA3015A.

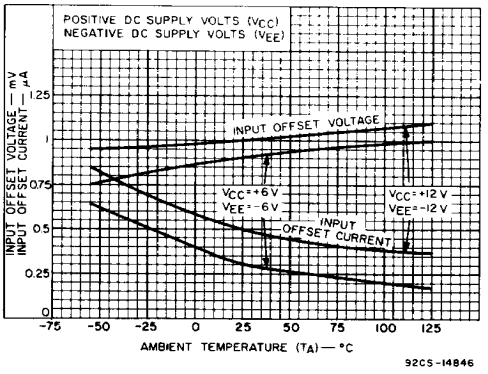


Fig. 2 — Input offset voltage and current

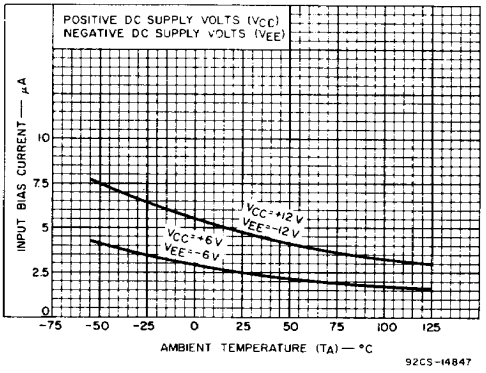


Fig. 3 — Input bias current

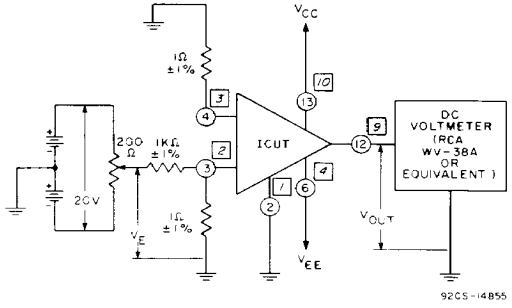


Fig. 4 — Input offset voltage, input offset voltage sensitivity, and and device dissipation test circuit.

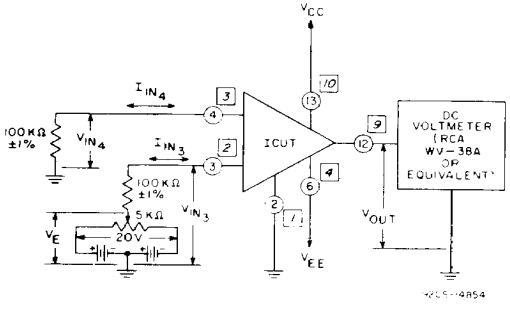


Fig. 5 — Input offset current and input bias current test circuit.

Procedure:

Input Offset Voltage

1. Adjust V_E for a DC Output Voltage (V_{OUT}) of 0 ± 0.1 volts.
2. Measure V_E and record Input Offset Voltage in millivolts as $V_E/1000$.

Input Offset Voltage Sensitivity

1. Adjust V_E for a DC Output Voltage (V_{OUT}) of 0 ± 0.1 volts.
2. Increase $|V_{CC}|$ by 1 volt and record output voltage (V_{OUT}).
3. Decrease $|V_{CC}|$ by 1 volt and record output voltage (V_{OUT}).
4. Divide the diference between V_{OUT} measured in steps 2 and 3 by the change in V_{CC} in steps 2 and 3.

$$\frac{V_{OUT}}{V_{CC}} = \frac{V_{OUT}\ (\text{Step 2}) - V_{OUT}\ (\text{Step 3})}{2\ \text{volts}}$$

5. Refer the reading to the input by dividing by Open Loop Voltage Gain (A_{OL}).

$$V_{IO}\ V_{CC} = \frac{V_{OUT}\ V_{CC}}{A_{OL}}$$

6. Repeat procedures 1 through 5 for the Negative Supply (V_{EE}).
7. Device Dissipation

$P_T = V_{CC}I_C + V_{EE}I_E$
I_C = Direct Current into Terminal 13 or *10*
I_E = Direct Current out of Terminal 6 or *4*

Procedure:

Input Bias Current and Input Offset Current

1. Adjust V_E for $|V_{OUT}| < 0.1$ V DC.
2. Measure and record V_E and V_{IN_4}
3. Calculate the Input Bias Current using the following equation:

$$I_{I4} = \frac{V_{IN_4}}{100\ k\Omega}$$

4. Calculate the Input Offset Current using the following equation:

$$I_{IO} = V_E\ 100\ k\Omega$$

TYPICAL DYNAMIC CHARACTERISTICS AND TEST CIRCUITS

Terminal Numbers in Circles are for CA3029A, CA3030A,
Italic Numbers in Square Boxes are for CA3010A, CA3015A.

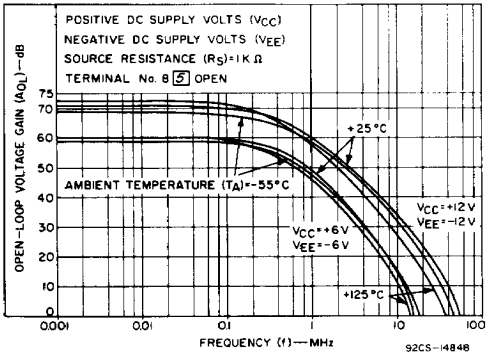


Fig. 6 — Open loop voltage gain vs. frequency for CA3015A, CA3016A

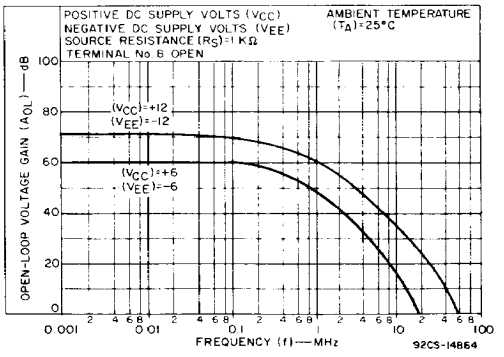
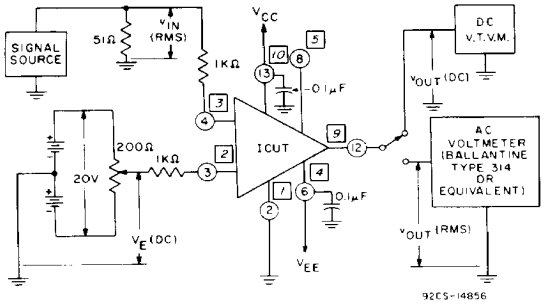


Fig. 7 — Open loop voltage gain vs. frequency for CA3029A and CA3030A.



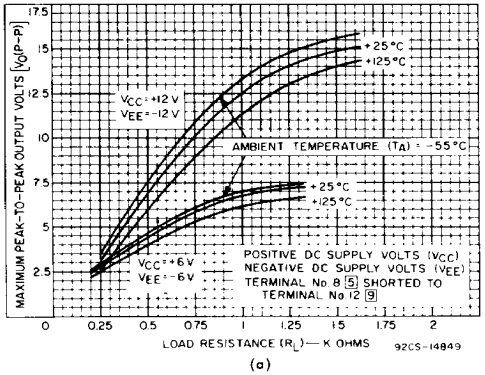
Procedure:

1. Adjust V_E for V_{OUT} = ±0.1 V DC.
2. Measure Open-Loop Differential Voltage Gain (A_{OL}) at f = 1 kHz

$$A_{OL} = 20 \log_{10} \frac{V_{OUT}}{V_{IN}}$$

3. Measure Maximum Peak-to-Peak Output Voltage at f = 1 kHz
4. Measure Open-Loop Bandwidth at -3 dB Point
   Reference Level = A_{OL} at 1 kHz

Fig. 8 — Open-loop differential voltage gain, maximum peak-to-peak output voltage, and open-loop bandwidth at -3 point test circuit.



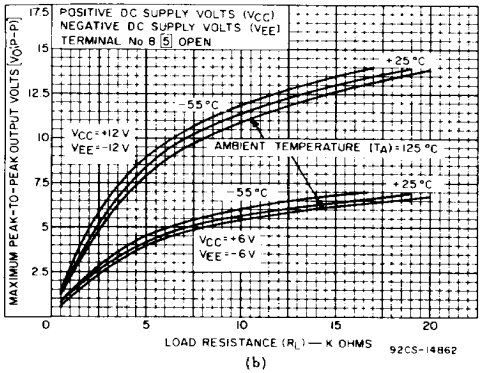


Fig. 9 — Maximum peak-to-peak output voltage vs. load resistance for CA3010A, CA3015A

TYPICAL DYNAMIC CHARACTERISTICS AND TEST CIRCUITS

Terminal Numbers in Circles are for CA3029A, CA3030A,
Italic Numbers in Square Boxes are for CA3010A, CA3015A.

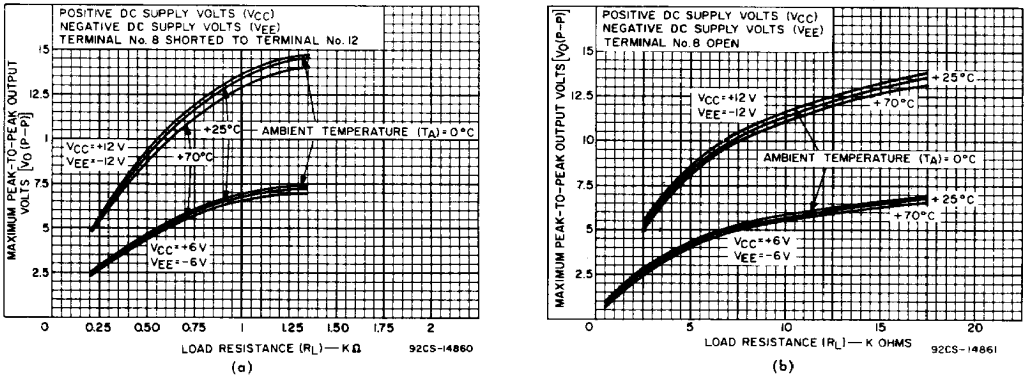
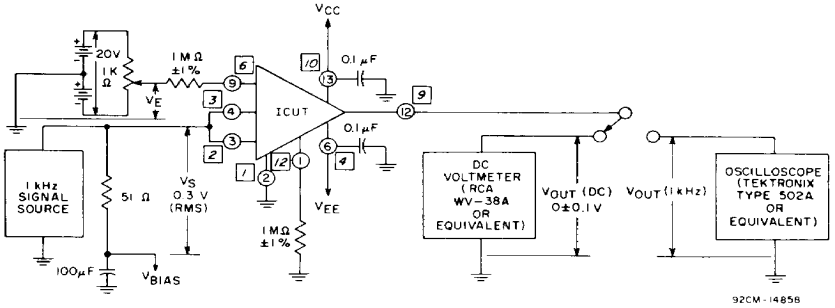


Fig. 10 — Maximum peak-to-peak output voltage vs. load resistance for CA3029A and CA3030A.



Procedures:

Common-Mode Rejection Ratio:

1. Set V_{BIAS} = 0. Adjust V_E for V_{OUT}(DC) = 0 ± 0.1 V.
2. Apply 1-kHz sinusodial input signal and adjust for V_S = 0.3 V (RMS).
3. Measure and record the RMS value of V_{OUT}. An oscilloscope is used for this measurement so that the output signal may be visually separated from noise output.
4. Calculate Common-Mode Voltage Gain:

$$A_{CM} = V_{OUT}/V_S$$

$$A_{CM} \text{ in dB} = -20 \log_{10} V_S/V_{OUT}$$

5. Calculate Common-Mode Rejection Ratio:

$$CMR \text{ in dB} = A_{DIFF} \text{ in dB} - A_{CM} \text{ in dB}.$$

Common-Mode Input-Voltage Range:

1. Calculate and record CMR for various positive and negative values of V_{BIAS} within the maximum limits shown on Page 2. The Common-Mode Input-Voltage Range limits are those values of V_{BIAS} at which CMR is 6 dB less than that calculated in Step 5 of the procedure given above.

Fig. 11 — Common-mode rejection ratio and common-mode input-voltage-range test circuit.

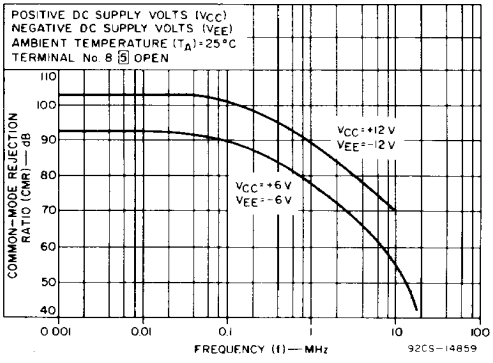


Fig. 12 — Common-mode rejection ratio vs. frequency.

TYPICAL DYNAMIC CHARACTERISTICS AND TEST CIRCUITS

Terminal Numbers in Circles are for CA3029A, CA3030A
Italic Numbers in Square Boxes are for CA3010A, CA3015A.

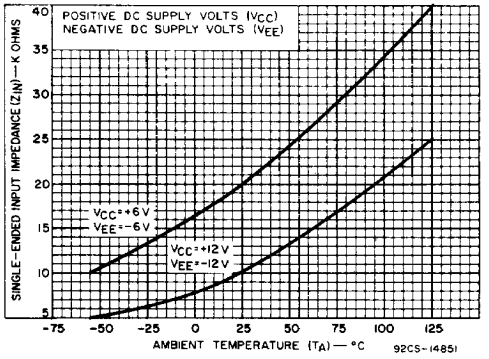


Fig. 13 — Single-ended input impedance vs. temperature.

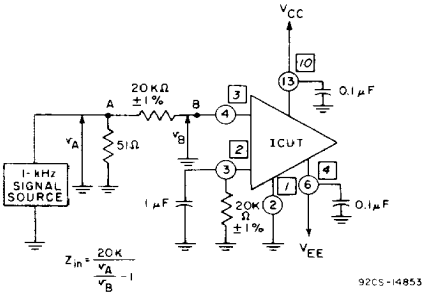
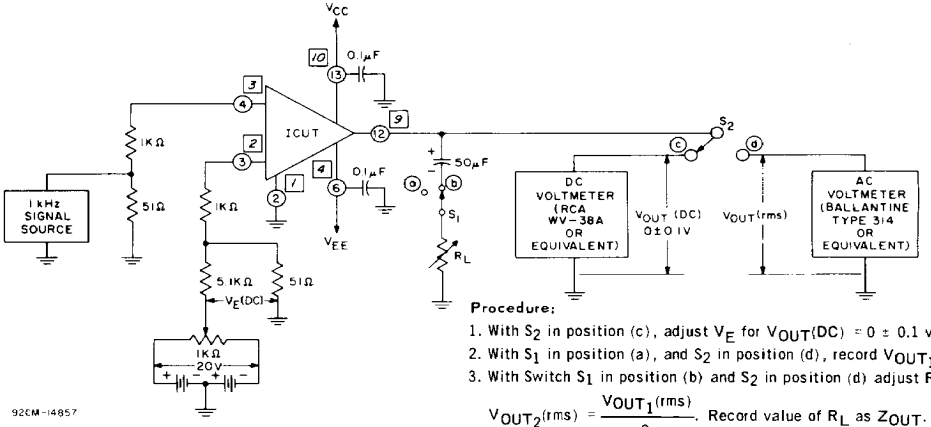


Fig. 14 — Single-ended input impedance test circuit.



Procedure:

1. With S_2 in position (c), adjust V_E for V_{OUT}(DC) = 0 ± 0.1 volt.
2. With S_1 in position (a), and S_2 in position (d), record V_{OUT_1}(rms).
3. With Switch S_1 in position (b) and S_2 in position (d) adjust R_L until $V_{OUT_2}(\text{rms}) = \frac{V_{OUT_1}(\text{rms})}{2}$. Record value of R_L as Z_{OUT}.

Fig. 15 — Output impedance test circuit.

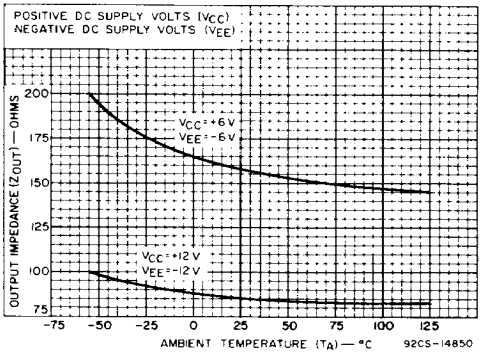


Fig. 16 — Output impedance vs. temperature.